Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/972,961	CHINO, NAOYOSHI	
Examiner	Art Unit	
Hai C. Pham	2861	

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	SEAR	CHED	
Class	Subclass	Date	Examiner
347	233-235, 239, 241, 244, 248	1/17/2006	НР
	255-258		
	136-137		
396	30	1/17/2006	HP
358	906	1/17/2006	HP

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
347	241, 256	1/20/2006	НР		
396	30	1/20/2006	HP		
PGPub T	PGPub Text Search		HP		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST Text Search	1/17/2006	HP	